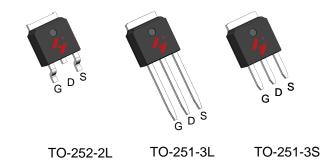


N-Channel Enhancement Mode MOSFET

Feature

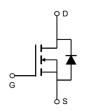
- 70V/70A $R_{DS(ON)} = 7.4 m\Omega(typ.)@Ves = 10V$
- 100% Avalanche Tested
- Reliable and Rugged
- Halogen Free and Green Devices Available (RoHS Compliant)

Pin Description



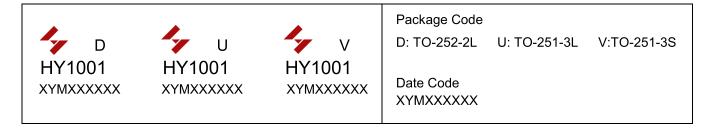
Applications

Power Management for Inverter Systems



N-Channel MOSFET

Ordering and Marking Information



Note: HUAYI lead-free products contain molding compounds/die attach materials and 100% matte tin plateTermi-Nation finish; which are fully compliant with RoHS. HUAYI lead-free products meet or exceed the lead-Free requirements of IPC/JEDEC J-STD-020 for MSL classification at lead-free peak reflow temperature. HUAYI defines "Green" to mean lead-free (RoHS compliant) and halogen free (Br or Cl does not exceed 900ppm by weight in homogeneous material and total of Br and Cl does not exceed 1500ppm by weight).

HUAYI reserves the right to make changes, corrections, enhancements, modifications, and improvements to this pr-oduct and/or to this document at any time without notice.



Absolute Maximum Ratings

Symbol	Parameter	Rating	Unit			
Common Rati	Common Ratings (Tc=25°C Unless Otherwise Noted)					
VDSS	Drain-Source Voltage		70	V		
Vgss	Gate-Source Voltage		±20	V		
TJ	Junction Temperature Range		-55 to 175	°C		
Тѕтс	Storage Temperature Range		-55 to 175	°C		
Is	Source Current-Continuous(Body Diode)	Tc=25°C	70	Α		
Mounted on L	arge Heat Sink					
Ірм	Pulsed Drain Current *	Tc=25°C	270	А		
	Oution Bridge	Tc=25°C	70	А		
lο	Continuous Drain Current	Tc=100°C	49.5	А		
-	M : 5 5: : ::	Tc=25°C	75	W		
Po	Maximum Power Dissipation Tc=100°C		37.5	W		
R _θ ic	Thermal Resistance, Junction-to-Case		2	°C/W		
R _{euA}	Thermal Resistance, Junction-to-Ambient **		110	°C/W		
Eas	Single Pulsed-Avalanche Energy ***	L=0.3mH	205	mJ		

Note: * Repetitive rating; pulse width limited by max. junction temperature.

** Surface mounted on FR-4 board.

*** Limited by TJmax , starting TJ=25°C, L = 0.3mH, Rg= 25Ω , Vgs =10V.

Electrical Characteristics (Tc = 25°C Unless Otherwise Noted)

Currala a l	Symbol Parameter Test Co		Test Conditions		HY1001		l locid
Symbol	Parameter	lest Conditions		Min	Тур.	Max	Unit
Static Cha	Static Characteristics						
BVDSS	Drain-Source Breakdown Voltage	V _{GS} =0V,I _{DS} =250	0μΑ	70	-	-	V
V _{DS} =		V _{DS} =70V,V _{GS} =0	ΟV	-	-	1	μΑ
IDSS	loss Drain-to-Source Leakage Current		TJ=125°C	-	-	50	μΑ
V _{GS(th)}	Gate Threshold Voltage	V _{DS} =V _{GS} , I _{DS} =250µA		2	3	4	V
Igss	Gate-Source Leakage Current	V _{GS} =±20V,V _{DS} =0V		-	-	±100	nA
RDS(ON)*	Drain-Source On-State Resistance	V _{GS} =10V,I _{DS} =40A		-	7.4	8.6	mΩ
Diode Cha	Diode Characteristics						
V _{SD} *	Diode Forward Voltage	I _{SD} =40A,V _{GS} =0V		-	0.87	1.1	V
trr	Reverse Recovery Time	1		-	24		ns
Qrr	Reverse Recovery Charge	- Isb=40A,dIsb/dt=100A/µs		-	29		nC



Electrical Characteristics (Cont.) (Tc =25°C Unless Otherwise Noted)

Symbol	Parameter	Took Conditions	HY1001		l lasia	
		Test Conditions	Min	Тур.	Max	Unit
Dynamic (Characteristics					
Rg	Gate Resistance	V _{GS} =0V,V _{DS} =0V,F=1 MHz	-	2.6	-	Ω
Ciss	Input Capacitance	V _{GS} =0V,	-	4200	-	
Coss	Output Capacitance	V _{DS} =25V,	-	285	-	рF
Crss	Reverse Transfer Capacitance	Frequency=1.0MHz	-	220	-	
td(ON)	Turn-on Delay Time		-	18	-	
Tr	Turn-on Rise Time	V_{DD} =30 V , R_{G} =4 Ω ,	-	50	-	no
td(OFF)	Turn-off Delay Time	IDS=40A,VGS=10V	-	60	-	ns
Tf	Turn-off Fall Time		-	42	-	
Gate Char	Gate Charge Characteristics					
Qg	Total Gate Charge	\/ -40\/ \/ -10\/	-	82	-	
Qgs	Gate-Source Charge	$V_{DS} = 48V, V_{GS} = 10V,$ $I_{D} = 40A$	-	23	-	nC
Q_{gd}	Gate-Drain Charge	ID-40A	-	26	-	

Note: *Pulse test, pulse width ≤ 300 us, duty cycle $\leq 2\%$



Typical Operating Characteristics

Figure 1: Power Dissipation

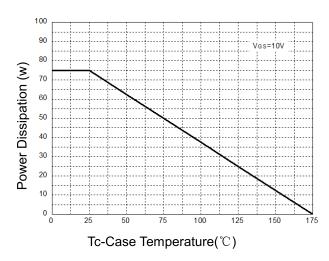


Figure 2: Drain Current

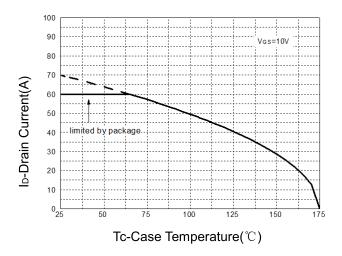


Figure 3: Safe Operation Area

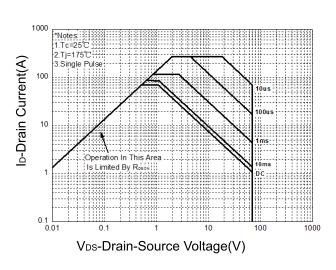


Figure 4: Thermal Transient Impedance

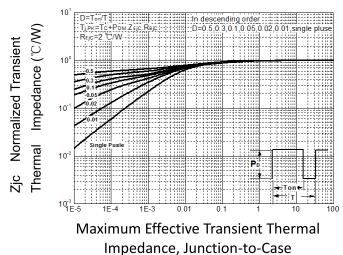


Figure 5: Output Characteristics

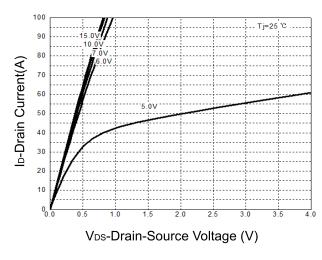
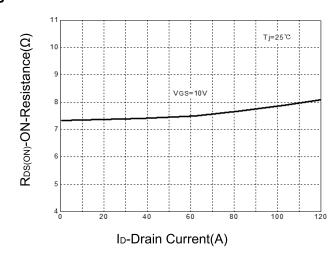


Figure 6: Drain-Source On Resistance





Typical Operating Characteristics(Cont.)

Figure 7: On-Resistance vs. Temperature

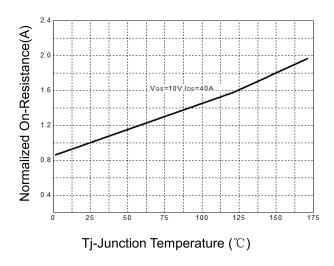


Figure 9: Capacitance Characteristics

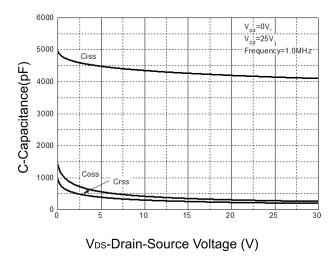


Figure 8: Source-Drain Diode Forward

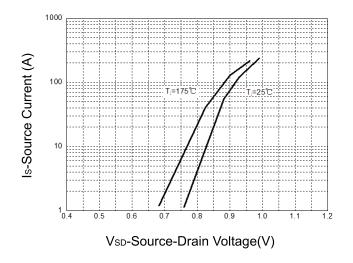
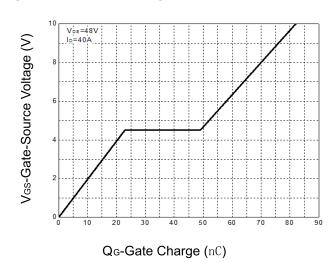
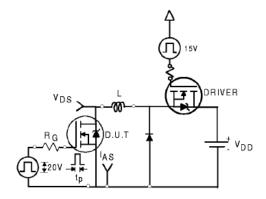


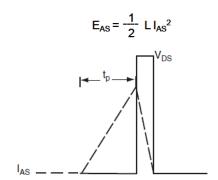
Figure 10: Gate Charge Characteristics



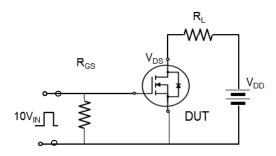


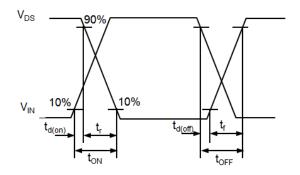
Avalanche Test Circuit



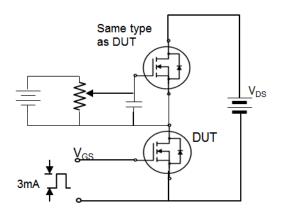


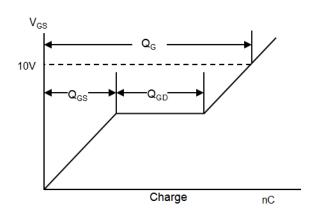
Switching Time Test Circuit





Gate Charge Test Circuit





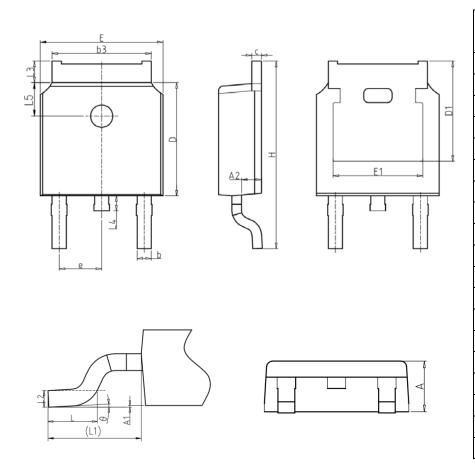


Device Per Unit

Package Type	Unit	Quantity
TO-252-2L	Tube	75
TO-252-2L	Reel	2500
TO-251-3L	Tube	75
TO-251-3S	Tube	75

Package Information

TO-252-2L

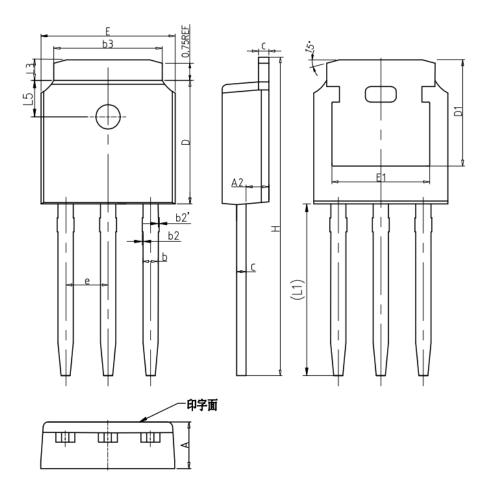


COMMON DIMENSIONS

SYMBOL		mm	
STINDOL	MIN	NOM	MAX
Α	2.20	2.30	2.40
A1	0.00	-	0.20
A2	0.97	1.07	1.17
b	0.68	0.78	0.90
b3	5.20	5.33	5.50
С	0.43	0.53	0.63
D	5.98	6.10	6.22
D1	5.30REF		
Е	6.40	6.60	6.80
E1	4.63	-	-
е		2.286BS0	
Н	9.40	10.10	10.50
L	1.38	1.50	1.75
L1		2.90REF	
L2	0.51BSC		
L3	0.88	-	1.28
L4	-	-	1.00
L5	1.65	1.80	1.95
θ	0°	-	8°



TO-251-3L

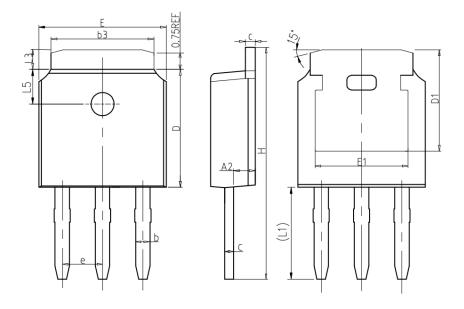


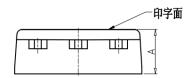
COMMON DIMENSIONS

SYMBOL	mm			
STIVIBOL	MIN	NOM	MAX	
А	2.20	2.30	2.40	
A2	0.97	1.07	1.17	
b	0.68	0.78	0.90	
b2	0.00	0.04	0.10	
b2'	0.00	0.04	0.10	
b3	5.20	5.33	5.50	
С	0.43	0.53	0.63	
D	5.98	6.10	6.22	
D1		5.30REF		
E	6.40	6.60	6.80	
E1	4.63	-	-	
е	2.286BSC			
Н	16.22	16.52	16.82	
L1	9.15	9.40	9.65	
L3	0.88	1.02	1.28	
L5	1.65	1.80	1.95	



TO-251-3S



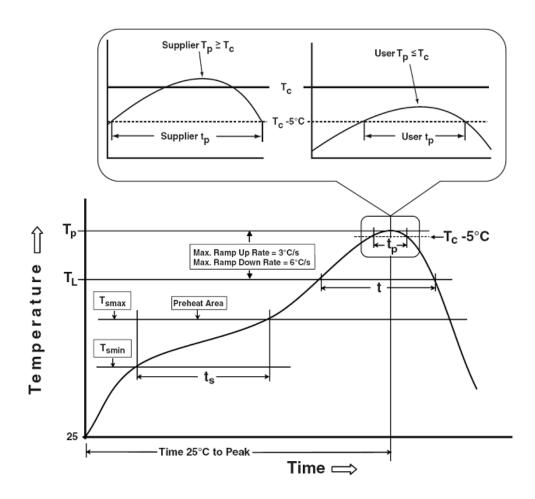


COMMON DIMENSIONS

CVMDOL	mm			
SYMBOL	MIN	NOM	MAX	
Α	2.20	2.30	2.40	
A2	0.97	1.07	1.17	
b	0.68	0.78	0.90	
b3	5.20	5.33	5.50	
С	0.43	0.53	0.63	
D	5.98	6.10	6.22	
D1		5.30REF		
E	6.40	6.60	6.80	
E1	4.63	-	1	
е		2.286BSC		
Н	10.00	11.22	11.44	
L1	3.90	4.10	4.30	
L3	0.88	1.02	1.28	
L5	1.65	1.80	1.95	



Classification Profile



Classification Reflow Profiles

Profile Feature	Sn-Pb Eutectic Assembly	Pb-Free Assembly		
Preheat & Soak	100 °C	150 °C		
Temperature min (T _{smin})	150 °C	200 °C		
Temperature max (T _{smax})				
Time (Tsmin to Tsmax) (t₅)	60-120 seconds	60-120 seconds		
Average ramp-up rate	3 °C/second max.	3°C/second max.		
(T _{smax} to T _P)	5 C/Second max.	o C/Second max.		
Liquidous temperature (T _L)	183 °C	217 °C		
Time at liquidous (t∟)	60-150 seconds	60-150 seconds		
Peak package body Temperature	See Classification Temp in table 1	Soc Classification Town in table 2		
(T _p)*	See Classification Temp in table 1	See Classification Temp in table 2		
Time (t _P)** within 5°C of the specified	20** seconds	30** seconds		
classification temperature (Tc)	20 seconds	30 seconds		
Average ramp-down rate (Tp to Tsmax)	6 °C/second max.	6 °C/second max.		
Time 25°C to peak temperature	6 minutes max.	8 minutes max.		
+				

^{*}Tolerance for peak profile Temperature (Tp) is defined as a supplier minimum and a user maximum.

^{**} Tolerance for time at peak profile temperature (t₂) is defined as a supplier minimum and a user maximum.



Table 1.SnPb Eutectic Process – Classification Temperatures (Tc)

Package	Volume mm³	Volume mm³
Thickness	<350	≥350
<2.5 mm	235 °C	220 °C
≥2.5 mm	220 °C	220 °C

Table 2.Pb-free Process – Classification Temperatures (Tc)

Package	Volume mm³	Volume mm³	Volume mm³
Thickness	<350	350-2000	≥2000
<1.6 mm	260 °C	260 °C	260 °C
1.6 mm – 2.5 mm	260 °C	250 °C	245 °C
≥2.5 mm	250 °C	245 °C	245 °C

Reliability Test Program

Test item	Method	Description
SOLDERABILITY	JESD-22, B102	5 Sec, 245°C
HTRB	JESD-22, A108	168 Hrs/500 Hrs/1000Hrs, Bias@150°C
PCT	JESD-22, A102	96 Hrs, 100%RH, 2atm, 121°C
TCT	JESD-22, A104	250/500/000 Cycles, -55°C~150°C

Customer Service

Worldwide Sales and Service: sales@hymexa.com Technical Support:Technology@hymexa.com

Huayi Microelectronics Co., Ltd.

No.8928, Shangji Road, Economic and Technological Development Zone, Xi'an, China

TEL: (86-029) 86685706 FAX: (86-029) 86685705 E-mail: sales@hymexa.com Web net: www.hymexa.com